

Online Technology Meeting on
Photonics Packaging and Testing

Characterization and test for PICs

24 April 2020

CONFIDENTIAL

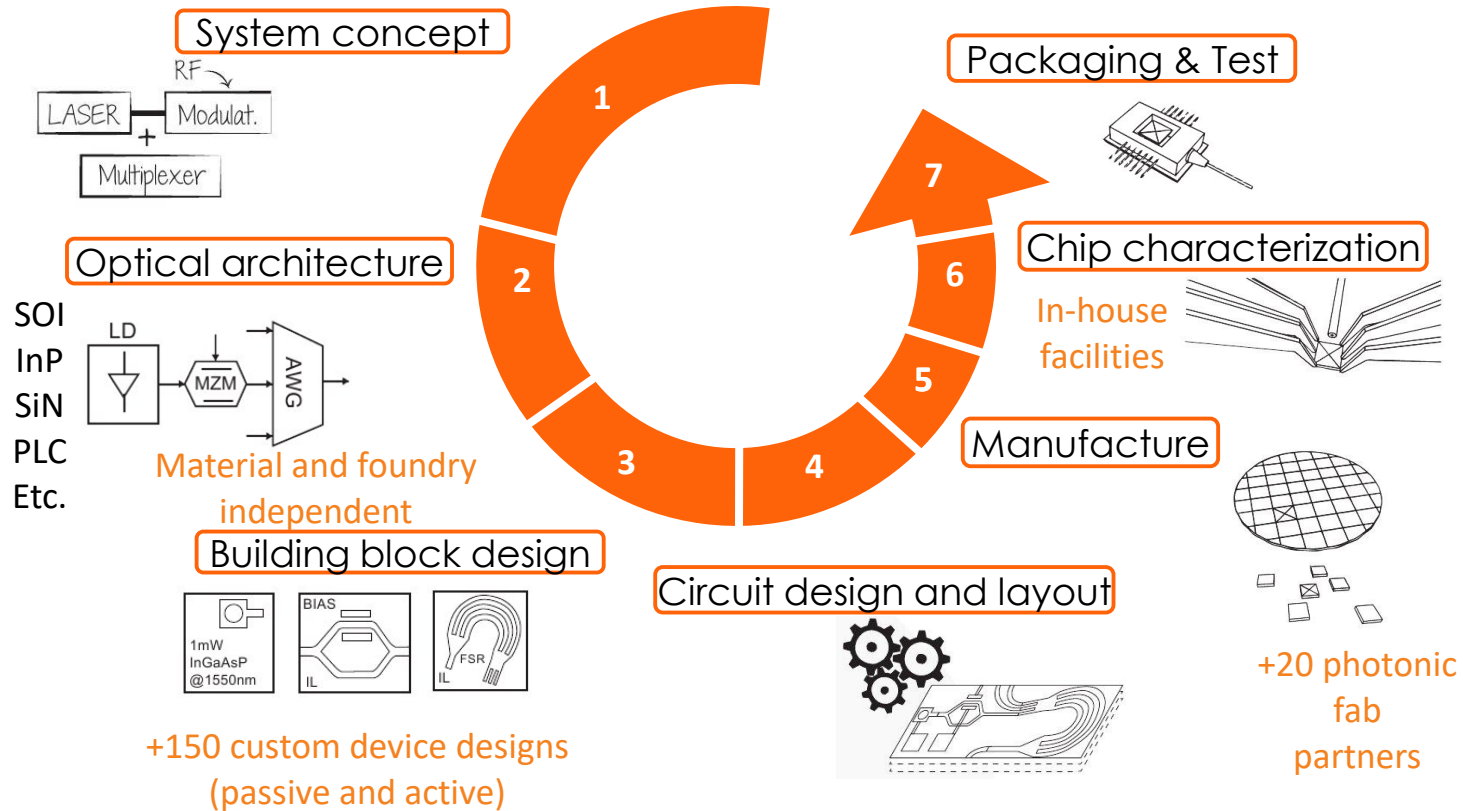


Who we are

- Founded in 2011.
- Offices in Spain, with a network of international partners.
- 17 members of extensive academic and industrial experience.
- 13+ years in the field of integrated optics and photonics.

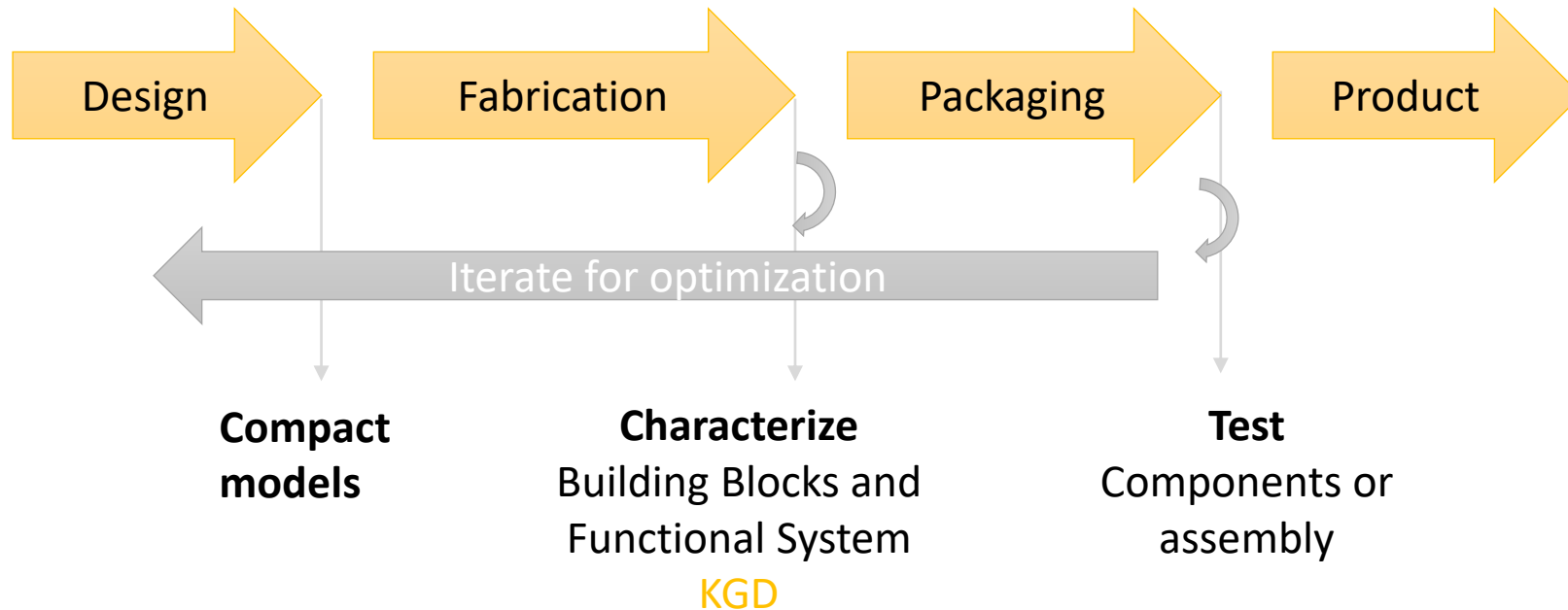


- Provide engineering services for the development of PICs



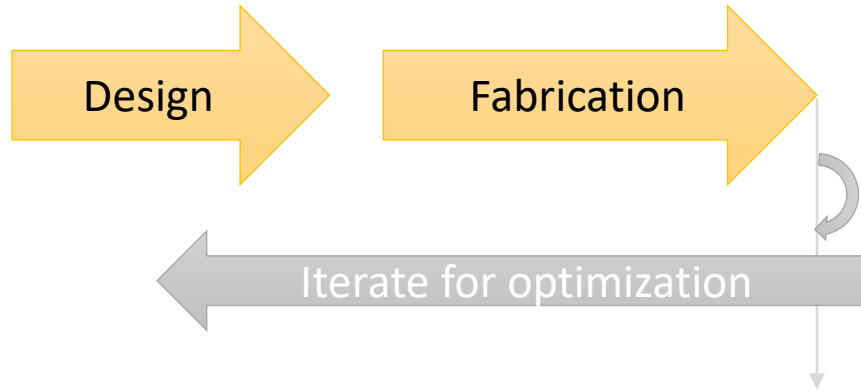
Why to characterize/test?

- There is a need for information on the performance of every phase to optimize the final product



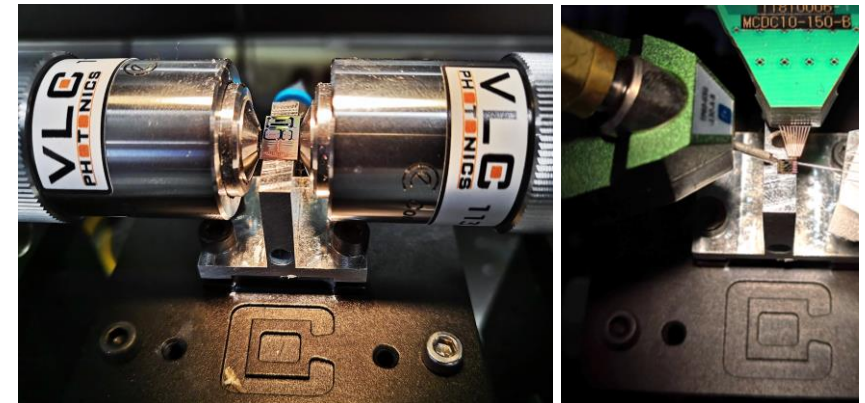
How to characterize?

- Characterize after fabrication at two levels

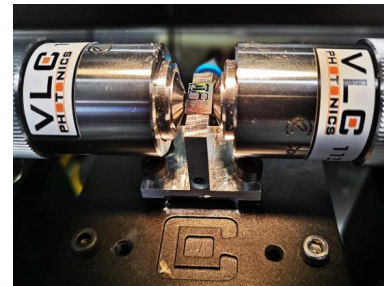


- Coupling and Propagation losses
- Spectral measurements
- PDL
- Laser output power
- PD Dark Current
- etc

Characterize
Wafer/Bar and
Bare Die
KGD

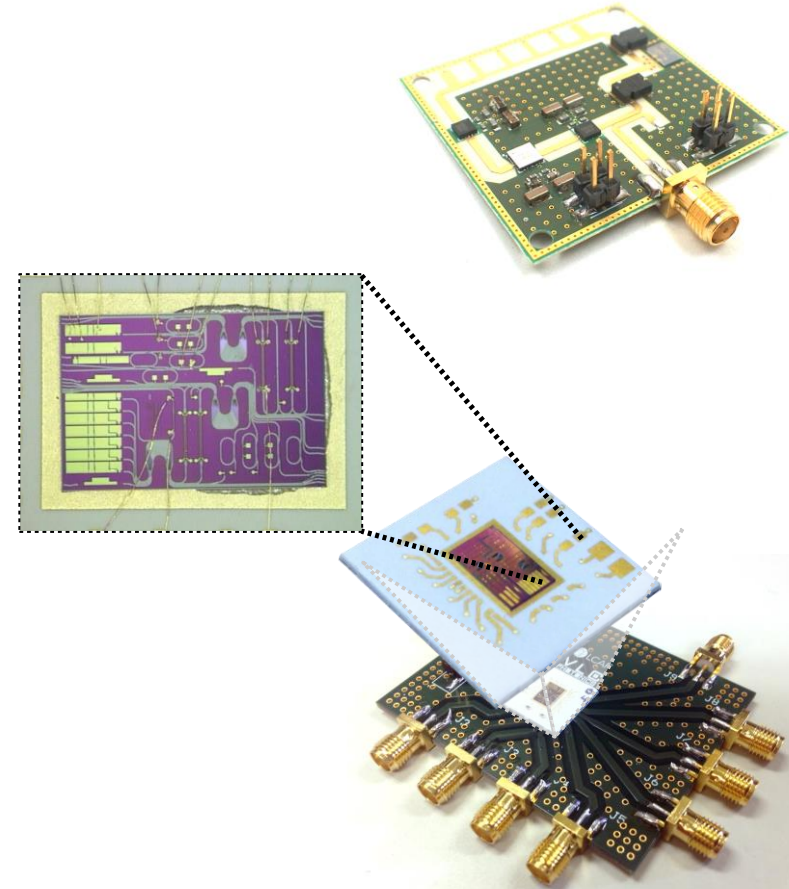
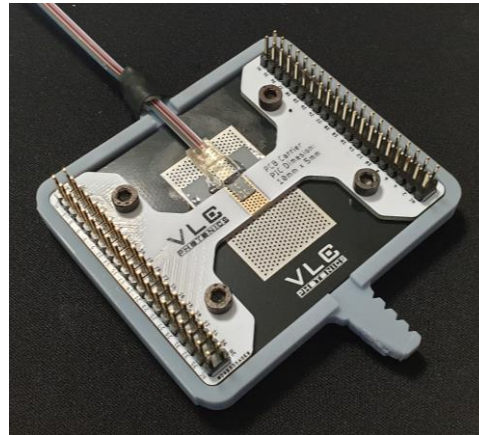
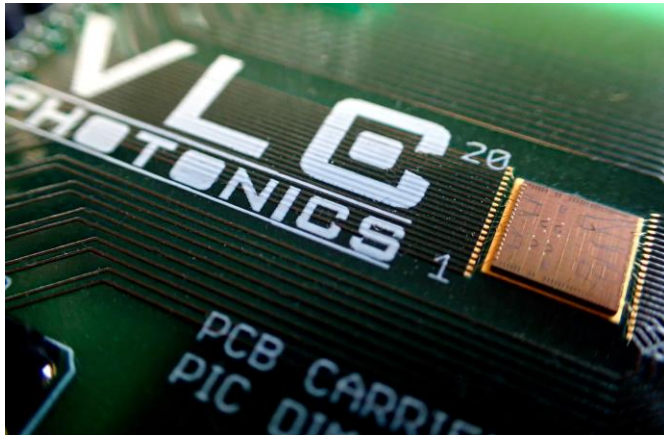


- Full characterization at VLC Photonics' facilities at cleanroom:
 - Bare die level
 - Package level
 - Wafer level (soon)
- 4 complete photonic characterization and test setups for bare chips, and 2 setups for wafer level testing.
- Basic thermal testing and cycling capabilities.



What we offer (II)

- Assembly boards for PIC testing
 - PCB and RF carriers
 - Manual and automated wirebonding
 - Basic fiber/array pigtailed



Thank you for your attention!



Contact details



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www.vlcphotonics.com



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